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ERROR CORRECTION IN HIGH SPEED ARITHMETIC*

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List of Symbols

E	Single iterative error
A	Generator of the arithmetic code
B	Number of codewords
m	Block length
r	Number of blocks
$\pm$	The polarity of error
k	The position of error
d	The number of erroneous digits
e_i	The distribution of error
S	Syndrome
h(x)	Hamming weight of x

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ABSTRACT

The errors due to a faulty high speed multiplier are shown to be iterative in nature. These errors are analyzed in various aspects. The arithmetic coding technique is suggested for the improvement of high speed multiplier reliability. Through a number theoretic investigation, a large class of arithmetic codes for single iterative error correction are developed. The codes are shown to have near-optimal rates and to render a simple decoding method. The implementation of these codes seems highly practical.

I. INTRODUCTION

General Background

A great deal of research has been done on the improvement of speed and reliability of computers. The fast arithmetic units, especially high speed multiplier and divider schemes, contribute significantly to the overall performance of digital computers. For reliability, the employment of signal redundancy via error detecting or correcting codes seems to be a promising approach (Avizienis, 1965) although other techniques, such as hardware redundancy, are also helpful.

Recent developments in carry-save adders and iterative adders speed up addition and subtraction. Recoding techniques, employing minimal-non-zero representation of operands, have been well adopted for speeding up the multiplication and division. Practical schemes for high speed multiplication such as the one proposed by MacSorley (1961) have been implemented in many computers.

In a high speed arithmetic unit, the multiplier is divided into blocks of two (or more) bits each and each block is multiplied to the multiplicant to form partial sums. The partial sums are appropriately shifted and added in a multi-input parallel adder with minimum carry provisions. The longer the blocks, the faster the multiplication, but the complexity of hardware increases sharply with the size of blocks. The speed of such a multiplier has been analyzed by Freeman (1967).

Arithmetic Codes

The objective of this study is to find an arithmetic coding scheme to improve the reliability of the high speed multiplier. Arithmetic codes are designed to detect or correct errors in digital computations. One such error may change many output digits by propagations. Single error correcting codes are summarized in Peterson (1965), and multiple independent error correcting codes have been studied by Barrows (1966), Mandelbaum (1967), Chang and Tsao-Wu (1968) and Chien, Hong, and Preparata (1968, 1969). Burst error correcting arithmetic codes have been investigated by Stein (1962), Chien (1964), and Mandelbaum (1965).

Arithmetic codes are of the form AN, where A is a fixed integer called the generator. N is an integer in the interval (0, B-1), and B is the number of code words. If the code length is n, B is the smallest integer such that $AB>2^n$. In the binary case, A is obviously an odd number. The error correcting capability of ordinary AN codes depends on the minimum distance of the code, which in turn depends on the generator A. A corrupted signal (correct signal plus error) modulo A is called the syndrome of the error which is the same as the error modulo A. Syndrome of an error, usually denoted as S, then leads to the correct decision of the error through the decoding algorithms.

The error pattern expected in high speed multiplier is quite different from either the multiple independent errors or the burst errors. The iterative errors we expect from the high speed multiplier scheme are multiple equally spaced errors. A number theoretic investigation will be used in analyzing these errors, synthesizing codes for such errors, and demonstrating an easy implementation and high efficiency of such codes.

Definition of Iterative Error

If a faulty circuit occurs in the high speed multiplier, the resulting error pattern in the output will be of the following special form. First, since partial products are shifted by multiples of block length, the erroneous digit in each block will occupy the same relative position.

Hence, it is called the Iterative Error. Second, since a faulty circuit (stuck on 0 or 1) contributes to either carry or borrow type mistakes but not both, the entire erroneous digits will be of the same polarity. Now let m = the length of a block in bits, r = the number of blocks, and let E be a single interative error.

<u>Definition 1</u> $E = \pm 2^k \sum_{i=0}^{r-1} e_i 2^{mi}$, where $0 \leq k < m$ and $e_i = 0$ or 1 for all i.

Of course, if $e_i = 0$ for all i, there exists no error. It is also feasible to extend the definition to cover multiple such error patterns occuring at the same time; for instance, a double iterative error would be $E = \pm 2^{k_1} \sum_{i=0}^{r-1} e_i 2^{mi} \pm 2^{k_2} \sum_{i=0}^{r-1} f_i 2^{mi}$, where $0 < k_1 < k_2 < m$, $e_i = 0$ or 1 and $f_i = 0$ or 1 for all i. Obviously any code that corrects all single iterative errors will detect all double iterative errors and vice versa. The following code for the detection of single iterative errors is well known.

<u>Theorem 1</u> The code with generator A, a divisor of 2^m-1 and $A>r$ detects all single iteration errors in r blocks of length m.

<u>Proof</u> It must be shown that $E \not\equiv 0 \bmod A$ for any error. Note that $2^{mi} \equiv 1 \bmod A$ for all i. Now, suppose $E \equiv \pm 2^k \sum_{i=0}^{r-1} e_i 2^{mi} \equiv 0 \bmod A$. Since 2 and A are relatively prime, we have $\sum_{i=0}^{r-1} e_i \equiv 0 \bmod A$. But $0 < \sum_{i=0}^{r-1} e_i \leq r < A$ and hence a contradiction. Q.E.D.

Example Let m = 6. The generators of single iterative error detecting codes are:

$A = 3$ if $r<3$		$A = 21$ if $7 \leq r < 21$	
$A = 7$ if $3 \leq r < 7$		$A = 63$ if $21 \leq r < 63$	

II. PRELIMINARY DISCUSSIONS

It follows from the definition that, to correct any single iterative error, one must correctly determine the polarity of the error, the position of the error, k, and the set of e_i's called the distribution of the error. For convenience, we introduce three notations, E_0, E_1 and E_2, respectively defined as

$$E_0 = E = \pm 2^k \sum_{i=0}^{r-1} e_i 2^{mi} \tag{1}$$

$$E_1 = 2^k \sum_{i=0}^{r-1} e_i 2^{mi} \tag{2}$$

and

$$E_2 = \sum_{i=0}^{r-1} e_i 2^{mi} \tag{3}$$

One can easily verify the relation, $E_0 = \pm E_1 = 2^k E_2$, representing the error in the order of decreasing complexity. The three different aspects of error analyzed in this chapter will serve as a basis for the forthcoming derivation of error correcting codes.

Polarity of Error, $\pm$

First, let us consider the case for integers $m = 2n + 1$ and $r \leq 2(2^n-1)$ for some $n \geq 1$. We will find a simple method with which the polarity can be uniquely determined. The same method will be used for the general case later.

Lemma 1 Let $m = 2n+1$ and $r \leq 2(2^n-1)$ for some $n \geq 1$, then $S \equiv E_0 \mod 2^m-1$ has less than or equal to n1's if and only if the polarity of error is positive.

Proof Let $S' \equiv E_2 \equiv \sum_{i=0}^{r-1} e_i 2^{mi} \mod 2^m-1$. Since e_i's are either 0 or 1, we have $0 \leq S \leq 2(2^n-1) < 2^m-1$. The maximum number of 1's S can have is therefore n.

Now $S'' \equiv E_1 \equiv 2^k E_2 \bmod 2^m-1$ is merely a cyclic shift of S' modulo 2^m-1, which does not affect the number of 1's in S'. Thus, if $E_0 = E_1$, S has less than or equal to n 1's. But if $E_0 = -E_1$, $-S' \equiv 2^m-1-S'$ which can not have less than $2n+1-n = n+1$ 1's. Q.E.D.

With the above discussion in mind, consider now a general case where there is no obvious relationship between m and r. Let ℓ be an integer less than r, then $r = s\ell + t$ where $s \geq 1$ and $0 \leq t < \ell$. Clearly,

$$E_2 = \sum_{i=0}^{r-1} e_i 2^{mi} \equiv \sum_{i=0}^{\ell-1} f_i 2^{mi} \bmod 2^{m\ell}-1 \tag{4}$$

where $0 \leq f_i \leq s + 1$ for all $0 \leq i < t$ and $0 \leq f_i \leq s$ for all $t \leq i < \ell$.

The Hamming weight of an integer I is defined as the number of 1's in the binary expression of I. Let w(x) be the maximum Hamming weight of I for all $0 \leq I \leq x$. Notice that w(x) is a non-decreasing function of x.

<u>Lemma 2</u> $w(x) = [\log_2(x+1)]$,*

<u>Proof</u> Clearly $w(x) = n$ if $2^n-1 \leq x < 2^{n+1}-1$ for some $n \geq 1$. Thus $n \leq \log_2(x+1) < n+1$ and $n = [\log_2(x+1)] = w(x)$. Q.E.D.

Define M(x) as the Hamming weight of x mod $2^{m\ell}-1$. $M(x) = M(2^k x)$ for any k, because 2^k amounts to a cyclic shift of 1's and 0's modulo $2^{m\ell}-1$. Rewriting Eq. (4), we get $0 \leq M(E_1) = M(E_2) \leq w(s+1)t + w(s)(\ell-t)$ and hence

$$M(E_1)_{max} = w(s)\ell + \{w(s+1) - w(s)\}t \tag{5}$$

---

*[a] denotes the integer part of a

<u>Theorem 2</u> Given m and r, if $\ell < r$ satisfies the condition, $M(E_1)_{max} < \frac{1}{2} m\ell$, then $M(E_0) < \frac{1}{2} m\ell$ if and only if the polarity of error is positive.

<u>Proof</u> If $E_0 = E_1$, the theorem follows from the hypothesis. If $E_0 = -E_1$, then $M(-E_1) = m\ell - M(E_1) \geq m\ell - M(E_1)_{max} > \frac{1}{2} m\ell$. Q.E.D.

The condition $M(E_1)_{max} < \frac{1}{2} m\ell$ is not as involved as it might seem. In fact, lemma 1 is a special case of this theorem. We know that $s = [\frac{r}{\ell}]$ and $t \equiv r \bmod \ell$. Also by lemma 2, $w(s+1) - w(s) = 1$ if and only if $s = 2^n-2$ for some $n > 1$. It is equal to zero otherwise. Given these facts, the table of maximum r's (r_{max}) for which ℓ satisfies the condition, is not difficult. Note that $M(E_1)_{max}$ is a non-decreasing function of r and hence ℓ and r_{max} are mutually non-decreasing functions of each other. From Table 1, one finds the smallest ℓ that satisfies the condition $M(E_1)_{max} < \frac{1}{2} m\ell$ via the first $r_{max} \geq r$ in the row of given m. The reason for the smallest ℓ is to maximize the rate of the code (see the section III).

<u>Position of Error, k</u>

We begin with the assumption that the number of error digits, $d = \sum_{i=0}^{r-1} e_i$ is given as well as $E_1 \bmod 2^m-1$. Let $S \equiv E_1 \equiv 2^k d \bmod 2^m-1$. We now derive a condition on r such that given d ($d \leq r$, necessarily) k can be uniquely decided from S.

Define T to be the smallest integer such that $2^x T \equiv T \bmod 2^m-1$ for any integer x in the range $0 < x < m$. Then, there must exist a least positive integer, y, such that x=y satisfies the above relation for T.

Table 1. r_{max} for m and ℓ

m ℓ	1	2	3	4	5	6	7
3	2	4	7	9	12	14	17
4	2	5	8	11	14	17	20
5	6	12	19	25	32	38	45
6	6	13	20	27	34	41	48
7	14	28	43	57	72	86	101
8	14	29	44	59	74	89	104
9	30	60	91	121	152	182	213
10	30	61	92	123	154	185	216
11	62	124	187	249	312	374	437
12	62	125	188	251	314	377	440
13	126	252	379	505	632	758	885
14	126	253	380	507	634	761	888
15	254	508	763	1017	1272	1526	1781
16	254	509	764	1019	1274	1529	1784

Lemma 3 y is the largest divisor, x_0, of m ($x_0 < m$) and $T = (2^m-1)/(2^{x_0}-1)$.

Proof By the division algorithm, $m = ay+b$ where $0 < a$ and $0 \leq b < y$. Now, $2^m T \equiv 2^{ay+b}T \equiv 2^b T \equiv T \bmod 2^m-1$. This implies that $b = 0$ and $m = ay$, for y is the least positive integer for the above relation to hold. Therefore, 2^y-1 divides 2^m-1 and

$$T \equiv 0 \bmod \frac{2^m-1}{2^y-1}.$$

Clearly $T = (2^m-1)/(2^{x_0}-1)$ is the minimum when x_0 is the largest divisor of m ($x_0 < m$). We must now show that $y = x_0$ for this T. First, $(2^{x_0}-1)T \equiv 0 \bmod 2^m-1$. Suppose $y < x_0$, then

$$T = \frac{2^m-1}{2^{x_0}-1} \equiv 0 \bmod \frac{2^m-1}{2^y-1}$$

which is a contradiction because $y < x_0$ implies that $(2^m-1)/(2^{x_0}-1) < (2^m-1)/(2^y-1)$. Q.E.D.

Theorem 3 Given d and $S \equiv 2^k d \equiv E_1 \bmod 2^m-1$, k can be uniquely decided if and only if $r < T$.

Proof If $r \geq T$, there is an error with $d = T$, for which $2^{x_0}T \equiv 2^{2x_0}T \equiv 2^{3x_0}T \ldots \bmod 2^m-1$, which results in a multiple solution for k. However, if $r < T$, and $2^k d \equiv 2^{k'} d \bmod 2^m-1$, then $(2^{k-k'}-1)d \equiv 0 \bmod 2^m-1$ and $0 \leq k-k' < m$. Since $d \leq r < T$, $k-k' = 0$ by the definition of T. Furthermore, $2^k d \equiv 0 \bmod 2^m-1$ only when $d = 0$, i.e., when there is no error. Q.E.D.

Table 2. T for given m

m	T	m	T	m	T
3	$2^3-1 = 7$	8	$2^4+1 = 17$	13	$2^{13}-1 = 8191$
4	$2^2+1 = 5$	9	$2^6+2^3+1 = 73$	14	$2^7+1 = 129$
5	$2^5-1 = 31$	10	$2^5+1 = 33$	15	$2^{10}+2^5+1 = 1057$
6	$2^3+1 = 9$	11	$2^{11}-1 = 2047$	16	$2^8+1 = 257$
7	$2^7-1 = 127$	12	$2^6+1 = 65$		

Distribution and the Number of Error Digits, d

In the previous section we have assumed that d was known. Now, we derive a condition on r such that d and the set of e_i's, namely the distribution, can be uniquely decided. We begin with a lemma which can be proved easily.

Lemma 4 If $(m,r) = 1$, the mapping from the set, $\{2^{mi} | 0 \leq i \leq r-1\}$, to the set, $\{2^j | 0 \leq j \leq r-1\}$, defined by $2^{mi} \equiv 2^j \bmod 2^r-1$ is one to one and onto.

Theorem 4 Let $(m,r) = 1$, $E_1 \neq 0$ and $S \equiv E_1 \bmod 2^r-1$. $S = 0$ if and only if $e_i = 1$ for all i, and when $S \neq 0$, S has d 1's. Furthermore, E_1 can be uniquely decided given k and S.

Proof By lemma 4, each term 2^{mi} maps to $2^{mi \bmod r}$ in one to one correspondence, and 2^k amounts to a cyclic shift which does not alter the number of 1's in S. Now given k and $S \neq 0$, $2^{-k}S \bmod 2^r-1$ can be uniquely mapped back to E_2, digit by digit, from which we obtain $E_1 = 2^k E_2$. If $S = 0$, $E_1 = \sum_{i=0}^{r-1} 2^{mi}$. Q.E.D.

III. CORRECTION OF SINGLE ITERATIVE ERROR

Now we are ready to synthesize codes for single iterative error correction. First, the A_1-code is shown with its error correcting ability demonstrated by a simple decoding algorithm. We then present some variations of this code. The rate (efficiency) considerations and a comparison of these codes are given with examples.

A_1-Code

As it was mentioned earlier, a successful correction of error depends on the correct decoding of the polarity, position, and distribution of error. A_1-Code is designed to do all these in the above order. Thus, from the syndrome we decipher $E_0 \pm E_1 = \pm 2^k E_2$.

Generator of the A_1-code is defined as $A_1 = LCM[(2^{m\ell}-1),(2^r-1)]$, where $r < T$ given in lemma 3, $(r,m) = 1$ and ℓ is the smallest integer satisfying the condition given by theorem 2. When m is given, $r < T$ (one may use Table 2) and $(r,m) = 1$, one finds ℓ from Table 1. The number of codewords is $B = [\frac{2^{mr}}{A}] + 1 \approx \frac{2^{mr}}{A}$ for large mr.

Theorem 5 The A_1-codes correct all single iterative errors.

Proof (Decoding Algorithm) Let a corrupted output be $K = AN + E_0$ and let $h(x)$ denote the Hamming weight of the integer x. $A = A_1$ in this case.

Step 1) Let the initial syndrome be $S_0 \equiv K \equiv AN + E_0 \bmod A$. If $h(S_0 \bmod 2^{m\ell}-1) < \frac{1}{2} m\ell$, the polarity is positive and otherwise negative. (By theorem 2.) If $S_0 = 0$, there is no error. (By theorem 3)

Step 2) Let $S_1 = S_0$ if the polarity is positive and let $S_1 = A - S_0$ if the polarity is negative. In either case $S_1 \equiv E_1 \bmod A$.

Step 3) Let $S_2 \equiv S_1 \equiv E_1 \bmod 2^r-1$.

$h(S_2) = d$ or, if $S_2 = 0$, $d = r$ (By theorem 4)

Step 4) Let $S_3 \equiv S_1 \bmod 2^m-1$. Since 2^m-1 divides $2^{m\ell}-1$ for any $\ell \geq 1$, $S_3 \equiv S_1 \equiv E_1 \equiv 2^k d \bmod 2^m-1$. Starting with d from the previous step, form $2^i d \bmod 2^m-1$ (cyclic shift of d). When $2^{i'} d = S_3$, $k = i'$ (By theorem 3)

Step 5) Now $E_2 \equiv 2^{-k}S_2 \mod 2^r-1$ (cyclic shift left).

If $S_2 = 0$, $E_2 = \sum_{i=0}^{r-1} 2^{mi}$.

If $S_2 \neq 0$, let

$$2^{-k}S_2 \mod 2^r-1 = \sum_{i=0}^{r-1} a_i 2^i \quad (a_i = 0,1)$$

$$E_2 = \sum_{i=0}^{r-1} a_i 2^{(\frac{1}{m} i \mod r)m} . \quad \text{(By theorem 4)}$$

Q.E.D.

One of the many interesting aspects of this code is that the decoding is very simple, which is quite unusual for ordinary arithmetic codes. In fact, the decoding requires essentially three shift registers of length m,r and mr each, plus some basic combinatorial threshold elements and a few constant-divisor divider circuits.

A_2-Code

Suppose a faulty multiplier has its kth position stuck either on 0 or 1. Assuming all inputs occur with equal frequency, the probability that this fault will actually contribute to an error digit in any particular block is very close to one half. Therefore, the probability that the entire blocks will contain the error digits, i.e., $E_0 = \pm 2^k \sum_{i=0}^{r-1} 2^{mi}$, is $(1/2)^r$. Define this type of error as a solid error, then the probability of the occurrence of a solid error is less than 1% if $r \geq 7$, or less than 0.1% as $r \geq 10$. It is apparently desirable to have a code that corrects all but solid iterative errors if a higher rate is achieved.

A modified code for given m and r is defined by the generator $A_2 = [2^{m\lambda}-1), (2^r-1)]$, where λ is the same as the ℓ for the A_1-code with m and r-1. Obviously $A_1 = A_2$ whenever $\ell = \lambda$, i.e., for given m, no r_{max} in Table 1 equals r-1. For example, if m = 6 and r = 20, $\lambda = \ell = 3$; but if m = 6 and r = 21, $\ell = 4$ and $r = \ell - 1 = 3$ (from Table 1). Hence, from now on, we assume that $r-1 = r_{max}$ for given m in Table 1 and $\lambda = \ell - 1$, when the A_2-code is used.

Theorem 6 The A_2-codes correct all but solid single iterative errors and detect solid error.

Proof Since for non-solid errors, d=r-1 is the maximum number of digits in error, given λ satisfies the condition for theorem 2. Thus $S_0 \neq 0$ and $S_2 = 0$ is the only case when the polarity is undecidable, but the solid error is detected. The rest of the cases follow the same decoding steps as the A_1-code. Q.E.D.

The A_2-codes are especially effective when the block length, m, is even. Notice that if m = 2n (for some $n \geq 2$), $T = \frac{2^{2n}-1}{2^n-1} = 2^n+1$. But (r,m) = 1 forces r to be odd < T, and so $r = 2^n-1$ is a likely candidate for the number of blocks. We mention here that $r = 2^n-1$ and m = 2n are relatively prime for most cases except when n = 6, 12, 18, 20 or 21, etc. The first column of Table 1 shows, and it is easy to prove that, for m = 2n and $\ell = 1$, $r_{max} = 2^n-2$, which makes $r = r_{max} + 1 = 2^n - 1$ be indeed suitable for A_2-codes.

A_3-Code

Even though the discussion in this section can be applied to any m, we limit the scope to the even m cases. The objective is to remodify the modified codes so that the resultant code will correct all the single iterative errors including the solid error. Define the generator of remodified code as $A_3 = A_2 \cdot A'$, where A' is called the remodifier factor. Of course, it is desirable to have a smaller A' for a higher rate. We redefine A' as an integer such that the solid error $E = \sum_{i=0}^{r-1} 2^{mi} = \frac{2^{mr}-1}{2^m-1} \not\equiv 2^x(-E) \bmod A'$, for any x.

Theorem 7 The A_3-codes correct all single iterative errors.

Proof When a solid error is detected by the syndrome modulo A_2, the syndrome modulo A' uniquely reveals the polarity. Hence, all the decoding steps are applicable. Q.E.D.

The reason behind employing remodified A_3-code instead of the original A_1-code is to gain a higher rate if possible. This requires that $\log_2 A' < m^*$. Because, for given m and $r = r_{max} + 1$, $A_1 \approx 2^m A_2$ for most cases (see example 2). Finding such A' for arbitrary m may be very difficult. However, possible candidates are 7, 23...etc., i.e., those numbers x for which $y \not\equiv -2^j y \bmod x$ for any j and $y \not\equiv 0$. A simple test shows that 7 fails to be an A'; for a solid error of $m = 2n$ and $r = 2^n-1$, becomes 0 mod 7.

Lemma 5 $A' = 23$ is a remodifier for $m = 2n$ $(n = 3,4,5,7,8,9)$.

Proof First, $\log_2 23 < 5 < m$ given. Second, for any $y \not\equiv 0 \bmod 23$, $y \not\equiv 2^x y \bmod 23$ for any x, because $\{2^x \bmod 23 = \text{prime}\}$ forms two mutually complementary cosets. We now have to prove that $\sum_{i=0}^{r-1} 2^{mi} \not\equiv 0 \bmod 23$ for all the given m's.

Since $r = 2^n-1$, this sum becomes $(2^{mr}-1)/(2^m-1) = (2^{2n(2^n-1)}-1)/(2^{2n}-1)$. Since 23 is a factor of $2^{11}-1$, it is sufficient to show that 11 and $2n(2^n-1)$ are relatively prime for the given n's. But the smallest 2^n-1 divisible by 11 is when $n = 10$ which is larger than all the given n values. Q.E.D.

Lemma 6 Let p be a prime. If -2 (but not 2) is primitive modulo p, $(2^{rm}-1)/(2^m-1) \not\equiv 0 \bmod p$ and $\log_2 p<m$; then $A' = p$ is a remodifier for any m and r.

Proof Let $(2^{rm}-1)/(2^m-1) \equiv x \not\equiv 0 \bmod p$. It is well known that if e is the least positive integer to satisfy $2^e-1 \equiv 0 \bmod p$, e divides p-1, but since 2 is not a primitive root of p, e is a proper divisor of p-1. Suppose $x \equiv -2^y x \bmod p$ for some y. Let $y = ae+b$ with $a \geq 0$, $0 \leq b < e$. If $b = 0$, then $2^y \equiv 1 \bmod p$ and we arrive at a contradiction that $x \equiv -x \bmod p$. If $b \neq 0$, then $x \equiv -2^b x \bmod p$ or $2^b \equiv -1 \bmod p$. Thus $2^{2b} \equiv 1 \equiv (-2)^{2b} \bmod p$, but e divides 2b and so $e = 2b < p-1$. This is a contradiction on the hypothesis that -2 is a primitive root of p. Q.E.D.

Rate Comparison and Examples

Rate or efficiency of a code is defined as

$$R = \frac{\text{number of code words in bits}}{\text{code length}} \tag{6}$$

We will first derive a sphere packing upper bound on the rate of single iterative error correcting codes. To correct all the errors, the syndrome of each distinct error pattern must also be distinct. This sets a lower bound on A, the generator. The total number of distinct single iterative errors is

$$2 \cdot m \cdot (2^r - 1) + 1 \tag{7}$$

For large m and r, this rapidly approaches $m2^{r+1}$. Hence $A \geq m2^{r+1}$, or the number of codewords is less than or equal to $2^{mr}/m2^{r+1}$. From Eq. (6)

$$R \leq \frac{\log_2(2^{mr}/m2^{r+1})}{mr} = 1 - \frac{1}{m} - \frac{1+\log_2 m}{mr} \tag{8}$$

This is a strict upper bound on the rate for large m and r. This shows that the upper bound approaches $1 - \frac{1}{m}$ for large r or 1 for large m and r.

Now consider the rate of A_1-code, for A_2 and A_3 codes are already improved versions of the former. At the worst case $[(2^{m\ell}-1), (2^r-1)] = (2^{m\ell}-1) \cdot (2^r-1)$. Hence, the rate is lower bounded as

$$R > \frac{mr-(m\ell+r)}{mr} = 1 - \frac{1}{m} - \frac{\ell}{r} \tag{9}$$

which is an encouraging result. Although ℓ is related to m and r, it clearly shows the tendency that the lower bound for fundamental code approaches $1 - \frac{1}{m}$ for large r and also approaches 1 for large m and r, which is exactly how the upper bound behaves. To be precise, let us estimate ℓ/r. Recall theorem 2 and Eq. (5). For large m we have $2w(s) \approx m$. But $w(s) \approx \log_2 \lceil \frac{r}{\ell} \rceil \approx \log_2 \frac{r}{\ell} \approx \frac{m}{2}$ and so $\ell \approx r \cdot 2^{-m/2}$. Thus, for large m, Eq. (9) becomes

$$R > - \frac{1}{m} - 2^{-m/2} \approx 1 - \frac{1}{m} \tag{10}$$

This demonstrates that indeed the A_1-code is nearly perfect. We formally state this as a theorem.

Theorem 8 The rate of the A_1-code assymtotically approaches the upper bound for large m.

Further comparison of the codes will be presented in the following two sets of examples. Some typical values for m and r are chosen. In Examples 1, we show A_1-codes with odd m's. Examples 2 compares the generators A_1, A_2, and A_3. In both cases, the approximate rate and the upper limit is presented for a verification of theorem 8, in Table 3.

Examples 1 A_1-Codes for m = odd

	(m,r)	ℓ	
a)	(3,2)	1	$A_1 = [(2^3-1),(2^2-1)] = (2^3-1)(2^2-1)$
b)	(5,18)	3	$A_1 = [(2^{15}-1),(2^{18}-1)]=(2^{15}-1)(2^{18}-1)/(2^3-1)$
c)	(7,13)	1	$A_1 = [(2^7-1),[2^{13}-1)] = (2^7-1)(2^{13}-1)$
d)	(9,58)	2	$A_1 = [(2^{18}-1),(2^{58}-1)]=(2^{18}-1)(2^{58}-1)/3$
e)	(11,62)	1	$A_1 = [(2^{11}-1),(2^{62}-1)] = (2^{11}-1)(2^{62}-1)$

Examples 2 Comparison of different codes for m = even. All the examples here have $\ell = 2$, $\lambda = 1$, $m = 2n$, $r = 2^n-1$.

f) (6,7)
$$\begin{cases} A_1 = [(2^{12}-1)(2^7-1)] = (2^{12}-1)(2^7-1) \\ A_2 = [(2^6-1)(2^7-1)] = (2^6-1)(2^7-1) \\ A_3 = (2^6-1)(2^7-1)\cdot 23 \end{cases}$$

g) (8,15)
$$\begin{cases} A_1 = (2^{16}-1)(2^{15}-1) \\ A_2 = (2^8-1)(2^{15}-1) \\ A_3 = (2^8-1)(2^{15}-1)\cdot 23 \end{cases}$$

h) (10,31)
$$\begin{cases} A_1 = (2^{20}-1)(2^{31}-1) \\ A_2 = (2^{10}-1)(2^{31}-1) \\ A_3 = (2^{10}-1)(2^{31}-1)\cdot 23 \end{cases}$$

i) (14,127) $A_3 = (2^{14}-1)(2^{17}-1)\cdot 23$

j) (16,255) $A_3 = (2^{16}-1)(2^{255}-1)\cdot 23$

k) (18,511) $A_3 = (2^{18}-1)(2^{511}-1)\cdot 23$

Table 3.

Comparison of actual rates with the upper bound[1]

A_1-Codes, odd m					A_3-Codes, even m				
	(m	r)	Rate	Upper Bound		(m	r)	Rate	Upper Bound
a	3	2	0.333	0.333 [2]	f	6	7	0.60	0.748
b	5	18	0.65	0.763	g	8	15	0.78	0.842
c	7	13	0.78	0.815	h	10	31	0.85	0.886
d	9	58	0.86	0.879	i	14	127	0.918	0.926
e	11	62	0.89	0.903	j	16	255	0.931	0.936
					k	18	511	0.943	0.945

[1] Calculated by Eq. (8) except for (m,r) = (3,2)

[2] For small m and r Eq. (7) is used for the bound $R \leq \frac{\log_2([\frac{2^{mr}}{A}]+1)}{mr}$

IV. CONCLUSION

The likely errors due to a faulty high speed multiplier are shown to be iterative in nature. These errors are analyzed in various aspects. An arithmetic coding technique to correct these iterative errors have been suggested for the improvement of reliability.

It was shown that this class of codes are nearly optimal in rates. The A_1-codes form the basic scheme from which the modified A_2-codes and the remodified A_3-codes are derived. It is shown that the A_2-codes generally achieve higher rates than the A_1-codes, at the small expense of not being able to correct a specific solid error. The A_3-codes, on the other hand, correct all the single iterative errors with usually higher rates than the A_1-codes. The latter two codes are especially useful for even block length.

The decoding is shown to be very simple. The encoding consists of premultipling either the multiplicand or the multiplier by the fixed generator A. Also, possibly losing a few bits, we may drop the LCM in the generator so that $A = (2^{m\ell}-1)(2^r-1)$ which is very easy to multiply. One can also multiply $(2^{m\ell}-1)$ to the multiplicand and (2^r-1) to the multiplier to achieve a faster encoding time. The implementation of these codes seem to be very promising.

V. REFERENCES

Avizienis, A., 1965, "A Study of Effectiveness of Fault-Detecting Codes for Binary Arithmetic," Tech. Report No. 32-711, Jet Propulsion Laboratory, California Institute of Technology, Pasadena, California.

Barrows, J. T., Jr., 1966, "A New Method for Constructing Multiple Error Correcting Linear Residue Codes," Report R-277, Coordinated Science Laboratory, University of Illinois, Urbana, Illinois.

Chang, S. H. and Tsao-Wu, N. T., 1968, "Discussion on Arithmetic Codes with Large Distance," IEEE PGIT-14.

Chien, R. T., 1964, "Linear Residue Codes for Burst Error Correction," IEEE Trans. on Information Theory, Vol. IT 10.

Chien, R. T., Hong, S. J. and Preparata, F. P., 1969, "Some Results in the Theory of Arithmetic Codes," submitted for publication, Report R-417, Coordinated Science Laboratory, University of Illinois, Urbana, Illinois.

Chien, R. T., Hong, S. J. and Preparata, F. P., 1968, "Some Contribution to the Theory of Arithmetic Codes," Proceedings of the First Annual Hawaii International Conference on Systems Sciences.

Freeman, H., 1967, "Calculation of Mean Shift for a Binary Multiplier Using 2,3, or 4 Bits at a Time," IEEE Trans., Vol. EC-16.

MacSorley, O. L., 1961, "High-Speed Arithmetic in Binary Computers," Proc. of IRE, Vol. 49, No. 1.

Mandelbaum, D., 1965, "Arithmetic Error Detecting Codes for Communication Links Involving Computers," IEEE Trans. on Communication Technology Vol. Com. 13.

Mandelbaum, D., 1967, "Arithmetic Codes with Large Distance," IEEE Trans. on Information Theory, Vol. IT-13, No. 2.

Peterson, W. W., 1965, "Error Correcting Codes," The M.I.T. Press, Cambridge, Massachusetts, 3rd Ed.

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13. ABSTRACT

The errors due to a faulty high speed multiplier are shown to be iterative in nature. These errors are analyzed in various aspects. The arithmetic coding technique is suggested for the improvement of high speed multiplier reliability. Through a number theoretic investigation, a large class of arithmetic codes for single iterative error correction are developed. The codes are shown to have near-optimal rates and to render a simple decoding method. The implementation of these codes seems highly practical.

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